imall

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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

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SPECIFICATION

- · Supplier : Samsung electro-mechanics
- Product : Multi-layer Ceramic Capacitor
- · Samsung P/N:
- CL05A225KP5NNNC

(Reference sheet)

- · Description :
- CAP, 2.2uF, 10V, ±10%, X5R, 0402

A. Samsung Part Number

		<u>CL</u> ①	<u>05</u> ②	<mark>4</mark> 3	<u>225</u> ④	<u>K</u> 5	<u>P</u> 6	<u>5</u> 7	<u>N</u> 8	<u>N</u> 9	<u>N</u> 10	<mark>C</mark> 11
1	Series	Samsung Multi-layer Ceramic Capacitor										
2	Size	0402 (inch c	ode)		L: '	1.00	± 0.05	mm			W:	0.50 ± 0.05 mm
3	Dielectric	X5R				8	Inner	elect	rode			Ni
4	Capacitance	2.2 uF					Term	inatio	n			Cu
5	Capacitance	±10 %					Platir	ıg				Sn 100% (Pb Free)
	tolerance					9	Prod	uct				Normal
6	Rated Voltage	10 V				10	Spec	ial				Reserved for future use
1	Thickness	0.50 ± 0.05 mm				1	Packa	aging				Cardboard Type, 7" reel

B. Structure & Dimension



Samsung P/N	Dimension(mm)								
Samsung F/N	L	W	Т	BW					
CL05A225KP5NNNC	1.00 ± 0.05	0.50 ± 0.05	0.50 ± 0.05	0.25 ± 0.10					

C. Samsung Reliablility Test and Judgement Condition

Capacitance Within specified tolerance 1 ^{Mt/2} ±10% / 0.5±0.1Vrms Tan δ (DF) 0.1 max. *A capacitor prior to measuring the cc treated at 150°C+0/-10°C for 1 hour a ambient air for 24±2 hours. Insulation 10,000Mohm or 100Mohm×//F Rated Voltage 60~120 sec. Resistance Whichever is smaller Appearance No abnormal exterior appearance Microscope (×10) Withstanding No dielectric breakdown or mechanical breakdown 250% of the rated voltage 250% Yoltage mechanical breakdown 500g·f, for 10±1 sec. 60~120 sec. Adhesive Strength No peeling shall be occur on the of Termination 500g·f, for 10±1 sec. 500g·f, for 10±1 sec. Solderability More than 75% of terminal surface is to be soldered newly SnAg3.0Cu0.5 solder 245±5°C, 3±0.3sec. Solder pot : 270±5°C, 10±1sec. Vibration Test Capacitance change : within ±7.5% Solder pot : 270±5°C, 10±1sec. From 10Hz to 55Hz (return : 1min.) Vibration Test Capacitance change : within ±5% Tan δ, IR : initial spec. Amplitude : 1.5mm From 10Hz to 55Hz (return : 1min.) Woisture Resistance Capacitance change : within ±12.5% With rated voltage Moisture Resistance Capacitance change : within ±12.5% With rated voltage					
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IR : 500Mohm or 12.5Mohm × μ F					
Whichever is smaller					
High Temperature Capacitance change : within ±12.5% With ^{100%} of the rated voltage					
Resistance Tan δ : 0.2 max Max. operating temperature					
IR : 1,000Mohm or 25Mohm × <i>μ</i> F 1000+48/-0hrs					
Whichever is smaller					
Temperature Capacitance change : within ±7.5% 1 cycle condition					
CyclingTan δ, IR : initial spec.Min. operating temperature	→ 25° C				
→ Max. operating temperature					
	→ 25 °C				
5 cycle test	→ 25°C				

X The reliability test condition can be replaced by the corresponding accelerated test condition.

D. Recommended Soldering method :

Reflow (Reflow Peak Temperature : 260+0/-5°C, 10sec. Max)

Product specifications included in the specifications are effective as of March 1, 2013. Please be advised that they are standard product specifications for reference only. We may change, modify or discontinue the product specifications without notice at any time.

So, you need to approve the product specifications before placing an order.

Should you have any question regarding the product specifications,

please contact our sales personnel or application engineers.

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The products listed in this Specification sheet are **NOT** designed and manufactured for any use and applications set forth below.

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- Aerospace/Aviation equipment
- 2 Automotive or Transportation equipment (vehicles, trains, ships, etc)
- 3 Medical equipment
- ④ Military equipment
- *⑤* Disaster prevention/crime prevention equipment
- *ⓐ* Any other applications with the same as or similar complexity or reliability to the applications set forth above.